

Qualification Report

Company Name : WIZnet Co., Ltd.

Product Name : SW5300 Package Type : 100 LQFP

Reported Date : Sep 25th ,2008





QRT Semiconductor Inc

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Reviewed by: M.G.Kim

Approved by: Y.W. Hwang



1. Qualification Test Summary

DEVICE NO : SW5300	PRODUCT TYPE :	P/	ACKAGE TYPE 100 LQFP	: S <i>F</i>	AMPLE LOTS 1 LOTS	•	DRT NO : TC-D-0808-0169	
FAB SITE :	ASS'Y SITE :		PURPOSE: SW5300 QUALIFICATION				DATE: Sep 25 th , 2008	
TEST RESULTS								
TEST MODE	TEST CONDITION		Test Time	S/S	NO. OF FAIL	FAIL RATE(%)	REMARKS	
LOW TEMPERATURE OPERATING LIFE	-40 °C ,V0 = 3 V4 = 1.8 V, VIH		504 h	77	0	0.00 %		

* The test results are based on customer's data

2. Qualification Test Item & Results

2.1 LTOL (Low Temperature Operating Life)

This test is intended to look for failures caused by hot carriers, and is typically applied on memory devices or devices with submicron device dimensions.

A total of 77 devices are completed 504 hours with no failure.



Test Condition	Reference Document	Duration	SS	Results
- 40 °C , V0= 3.3 V V4 = 1.8 V,VIH = 3.3 V	JESD22-A108-C	504 h	77	PASS

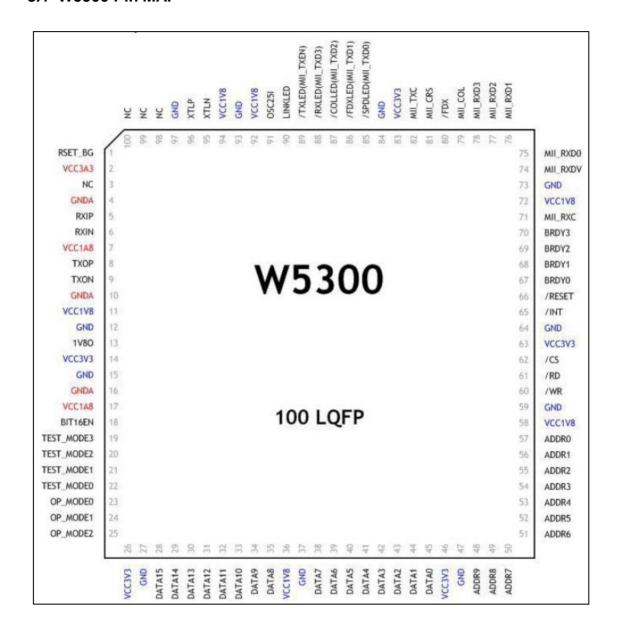


3. LTOL Test Conditions

 Frequency: 1 MHz ADDR9" { force { format RZ; start 150 ADDR8" { force { format RO; start 150 	, . , , ,
♦. Signal Rate : 1 000 ns	nat Condition
Vector Type : ATPG_SEQ.ftl + ATPG_short.ftl + scan_chain.ftl Test Vector 3개를 SUM 하여 진행 함.	
VCC3A3 (V0) :3.3 V VCC1A8 (V4) : 1.8 V	VIH: 3.3 V VIL: 0 V
LTOL Board Density: 80 ea / Board	Load S/S : 77 ea / Board

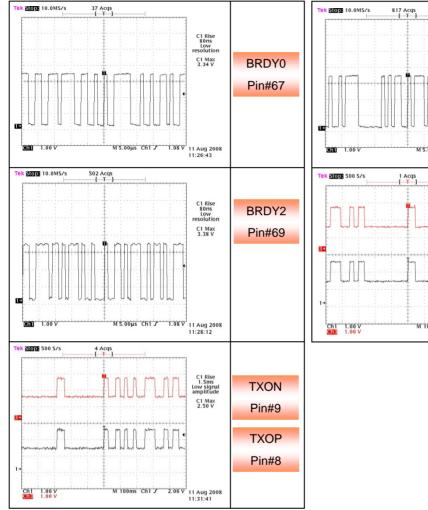


3.1 W5300 Pin MAP





3.2 LTOL timing sample chart





Quality Reliability Technology

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World Class Reliability Testing & Failure
Analysis Company